

Notice of References Cited	Application/Control No. 10/560,989	Applicant(s)/Patent Under Reexamination NONAKA ET AL.	
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U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-			
	B	US-			
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FOREIGN PATENT DOCUMENTS

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	N	2003-105513	04-2003	Japan	Fujita Nobuhiro et al.	-----
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NON-PATENT DOCUMENTS

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